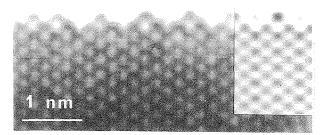
14.4-5 HIGH RESOLUTION SURFACE IMAGING. By L.D. Marks, Dept. of Physics, Arizona State University, Tempe, AZ 85287, U.S.A.

With the advent of high resolution electron microscopes with good signal-to-noise characteristics below 2Å, it has recently proved possible to directly resolve surface structure on metals (Marks, L.D. and Smith, D.J., Nature 303 316 (1983)). When coupled with detailed image simulations (Marks, L.D., Surface Science in press), local information including direct measurement of surface relaxations (Marks, L.D., Physical Review Letters <u>51</u> 1000 (1983) and Figure 1) and inhomogeneous surface strains (Marks, L.D., Heine, V. and D.J. Smith, submitted to Physical Review Letters) has proved possible. The required conditions for obtaining this information are very localised electron-optical imaging (Marks, L.D., Ultramicroscopy in press) and a column approximation for the dynamical diffraction. The latter depends upon a good zone axis orientation, and can be explained (Marks, L.D., submitted to Acta Cryst) by a swift electron analysis based upon spherical wave X-ray diffraction theory (e.g. Pinsker, Dynamical Scattering of X-rays in crystals (1978) and Azaroff et al, X-ray diffraction (1974)).

In this paper some of the recent results of high resolution imaging of gold surfaces will be described, concentrating upon the importance of local strains and surface dislocations, and the necessary conditions for the diffraction to obey a column approximation based upon an electron wavepacket scattering model briefly described.

2 x 1



<u>Figure 1</u> Experimental image of an Au(110) surface showing local 2x1 reconstruction with a numerical image simulation to the right (see Marks, L.D., Phy Rev Lett. <u>51</u>, 1000 (1983).  $\begin{array}{rcl} \textbf{14.4-6} & \textbf{HIGH RESOLUTION ELECTRON MICROSCOPIC STUDY} \\ \textbf{OF V}_{013}. & \textbf{By T. Ohno, Y.Nakamura and } \underbrace{\textbf{S. Na-gakura, Department of Metallurgy, Tokyo Institute of Technology, Oh-okayama, Meguro-ku, Tokyo 152, Japan.} \end{array}$ 

Structure images of  $V_cO_{1,5}$  (monoclinic, C2/m, a=11.922, b= 3.680, c=10.138 A and  $\beta=100.87\,^\circ)$  were taken with the aid of Ultra-High-Vacuum High-Resolution 1 MV Electron Microscope with the cut-off resolution 1 4 Å. The specimen was prepared by reducing a powder mixture of  $V_2O_2$  and  $V_2O_3$  in hydrogen at 670°C for 3 days, and crushed in acetone to make thin flakes for observation. In the structure image taken along the b axis, indivisual V atom rows as well as tunnels could be resolved clearly, although O atom rows did not give image contrast. The atomic scattering factor depends strongly on the electron state of atoms in the low scattering angle region. By using this fact, the effect of electron state on the structure image was investigated by comparing the observed images and simulated images produced by giving various largest and simulated images produced by giving varies and simulated images produced by giving varies shown that the neutral model  $V_0^{-1}$  explained more satisfactorily the image contrast than the ionized model  $V_2^{-1}V_2^{-1}V_2^{-1}$ . This is in accordance with the previous electron Alffraction result on  $V_{-0}$  (Y. Hirotsu, H. Sato and S. Nagakura, Modulated Structures-1979 : AIP Conf. Proc. No. 53, p. 75). A modification of V  $O_{13}$  was found, and its structure was analysed. This is orthorhombic with a=11. 922, b=19.912 and c=3.680 A and belongs to the space group Cmma. Approximate atom positions were determined. This structure can be derived from the structure of  ${\rm V_2O_5}$ by removing all the atoms on every third (001) oxygen atom plane and then introducing the crystallographic shear  $(1/2)[0\bar{1}\bar{1}]$ , instead of  $(1/6)[\bar{1}0\bar{3}]$  in the case of normal V<sub>6</sub>0<sub>13</sub>.

14.4-7 THE STRUCTURES OF SOME COMPLEX OXIDES CONTAINING NIOBIUM FROM HIGH RESOLUTION ELEC-TRON MICROGRAPHS. By M. Sundberg, Department of Inorganic Chemistry, University of Stockholm, Stockholm, Sweden.

The performance of modern high resolution electron microscopes enables a point-to-point resolution of 2-2.4 Å. In many materials the separations between heavier atoms in the structure can thus be resolved, and micrographs recorded under certain conditions can be interpreted on the basis of a reliable structure model. However, the interpretation of an image should be checked by matching observed and calculated images. It is also important to consider the chemical soundness of the model. For example, without reasonable assumptions about the coordination of the heavy cations, it is difficult to find a plausible distribution of light anions.

Some examples of complex oxides will be presented which illustrate HREM image interpretation of crystal and defect structures at the atomic level. All these phases have one short unit cell axis which is a favourable line of projection.

The crystal structure of  $NaNb_7O_{18}$  has been derived from HREM images and verified by multislice calculations of simulated images. Later, a refinement from X-ray powder data was made. The structure is related to that of  $NaNb_{13}O_{33}$ . Sodium atoms are located in the tunnels. (Marinder and Sundberg, Acta Cryst. In press.)